Application No. Applicant(s) ROY ET AL. 10/789,336 Notice of Allowability Examiner Art Unit Alexander G. Ghyka 2812 -- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308. 1. This communication is responsive to . ALEXANDER GHYKA 2. The allowed claim(s) is/are 1-56. PRIMARY EXAMINER 3. The drawings filed on 27 February 2004 are accepted by the Examiner. 4. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) 🔲 All b) Some\* c) None 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 3. Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)). \* Certified copies not received: \_\_\_\_\_. Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application. THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient. 6. CORRECTED DRAWINGS (as "replacement sheets") must be submitted. (a) including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached 1) hereto or 2) to Paper No./Mail Date (b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d). 7. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL. Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 5. Notice of Informal Patent Application (PTO-152) 2. Notice of Draftperson's Patent Drawing Review (PTO-948) 6. Interview Summary (PTO-413). Paper No./Mail Date 3. Information Disclosure Statements (PTO-1449 or PTO/SB/08), 7. X Examiner's Amendment/Comment Paper No./Mail Date 4. Examiner's Comment Regarding Requirement for Deposit 8. X Examiner's Statement of Reasons for Allowance of Biological Material 9. Other .

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## **DETAILED ACTION**

## **EXAMINER'S AMENDMENT**

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Deborah W. Wenocur on June 6, 2005.

The application has been amended as follows:

Cancel Claims 57-76.

## Allowable Subject Matter

The following is an examiner's statement of reasons for allowance: None of the cited prior art references, singly or in combination, anticipate or make obvious, the following limitations: said wafer portion having a first semiconductor surface region of said second surface directly atop said first doped region, and having a second semiconductor surface region of said second surface directly atop said second doped region, said voltage contrast being observable on a charged particle beam image, wherein the method comprises depositing an insulator layer atop said etched first semiconductor surface region and said etched second semiconductor surface region; and forming an image of said first doped region and second doped region, said first doped second semiconductor surface region;

region being unbiased electrically from said second doped region as required by some of the present claims. Moreover the cited prior art references, singly or in combination, do not anticipate or make obvious the following limitation: milling said trench into said wafer portion at a first particle beam energy and a first particle beam current for a first milling time period, said bottom trench surface after said first milling time portion being approximately 10 microns separated from said top surface of said doped region, milling said trench at a lower second particle beam, while visually monitoring charged particle beam induced secondary emission levels, and halting said milling when a contrast in secondary emission levels between said doped region and said remaining region becomes noticeable as required by some of the present claims. Therefore, Claims 1-56 are allowable.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

## Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Alexander G. Ghyka whose telephone number is (571) 272-1669. The examiner can normally be reached on Monday through Thursday during general business hours.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael Lebentritt can be reached on (571) 272-1873. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

AGG June 6, 2005 ALEXANDER GHYKA PRIMARY EXAMINER